

**Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

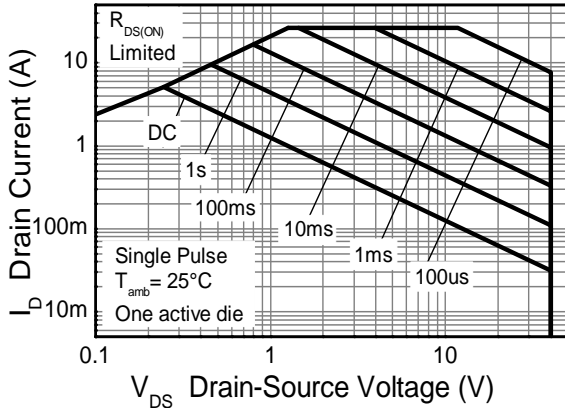
Characteristic			Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage			V <sub>DSS</sub>	40	-40	V
Gate-Source Voltage			V <sub>GSS</sub>	±20	±20	
Continuous Drain Current	V <sub>GS</sub> = 10V	(Notes 6 & 8)	I <sub>D</sub>	5.8	-5.8	A
		T <sub>A</sub> = +70°C (Notes 6 & 8)		4.38	-4.52	
		(Notes 5 & 8)		4.2	-4.2	
		(Notes 5 & 9)		5.3	-5.3	
Pulsed Drain Current	V <sub>GS</sub> = 10V	(Notes 7 & 8)	I <sub>DM</sub>	24.1	-24.9	
Continuous Source Current (Body Diode)			(Notes 6 & 8)	I <sub>S</sub>	2.5	
Pulsed Source Current (Body Diode)			(Notes 7 & 8)	I <sub>SM</sub>	24.1	-24.9

**Thermal Characteristics**

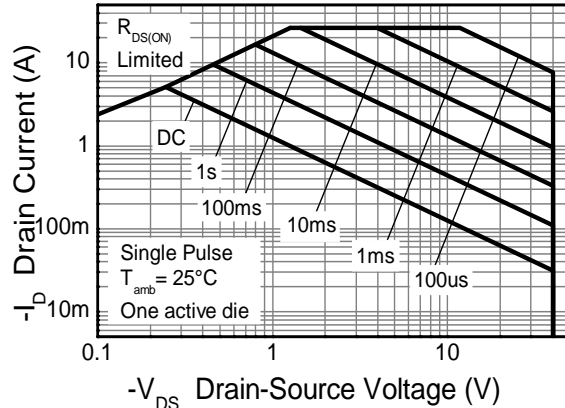
Characteristic	Symbol	Value	Unit
Power Dissipation Linear Derating Factor	P <sub>D</sub>	(Notes 5 & 8)	1.25
		(Notes 5 & 9)	1.8
		(Notes 6 & 8)	2.14
Thermal Resistance, Junction to Ambient	R <sub>θJA</sub>	(Notes 5 & 8)	100
		(Notes 5 & 9)	70
		(Notes 6 & 8)	58
Thermal Resistance, Junction to Lead	R <sub>θJL</sub>	51	°C/W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	

- Notes:
5. For a device surface mounted on 25mm × 25mm × 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
  6. Same as Note 5, except the device is measured at t ≤ 10 sec.
  7. Same as Note 5, except the device is pulsed with D = 0.02 and pulse width 300µs.
  8. For a dual device with one active die.
  9. For a device with two active die running at equal power.
  10. Thermal resistance from junction to solder-point (at the end of the drain lead).

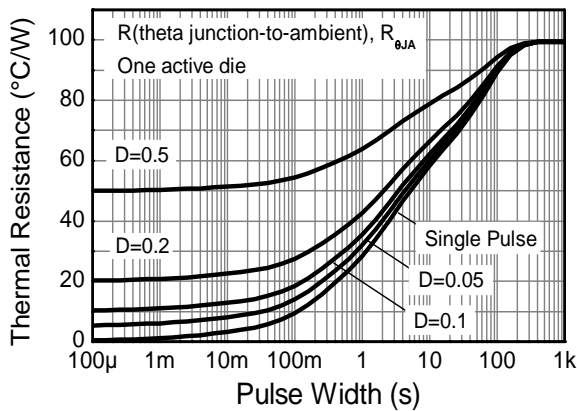
**Thermal Characteristics (continued)**



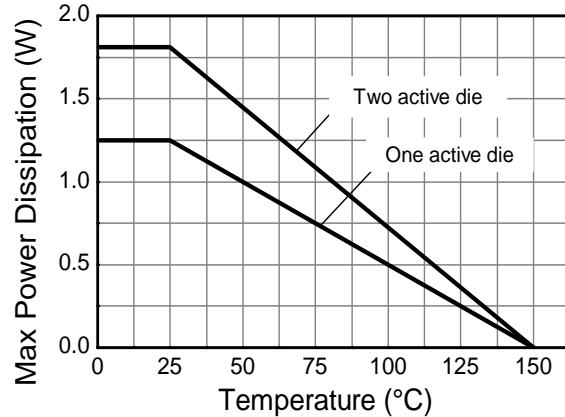
**N-channel Safe Operating Area**



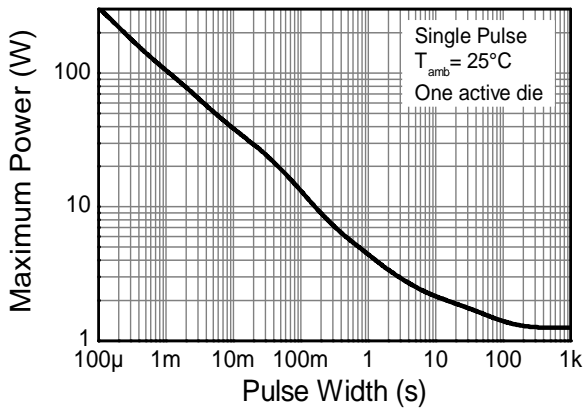
**P-channel Safe Operating Area**



**Transient Thermal Impedance**



**Derating Curve**



**Pulse Power Dissipation**

**Electrical Characteristics** (Q1 N-Channel) (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b> (Note 11)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	40	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	—	—	1.0	μA	V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±100	nA	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS</b> (Note 11)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	0.8	1.3	1.8	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	—	20	45	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 3A
			33	60		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 3A
Forward Transfer Admittance	Y <sub>FS</sub>	—	12.6	—	S	V <sub>DS</sub> = 5V, I <sub>D</sub> = 3A
Diode Forward Voltage (Note 11)	V <sub>SD</sub>	—	0.7	1.0	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1A
<b>DYNAMIC CHARACTERISTICS</b> (Note 12)						
Input Capacitance	C <sub>ISS</sub>	—	1,790.8	—	pF	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>OSS</sub>	—	160.6	—	pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>	—	120.5	—	pF	
Gate Resistance	R <sub>G</sub>	—	1.03	—	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge	Q <sub>G</sub>	—	37.56	—	nC	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 20V, I <sub>D</sub> = 3A
Gate-Source Charge	Q <sub>GS</sub>	—	7.8	—	nC	
Gate-Drain Charge	Q <sub>GD</sub>	—	6.6	—	nC	
Turn-On Delay Time	t <sub>D(ON)</sub>	—	8.08	—	ns	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 20V, I <sub>D</sub> = 3A
Turn-On Rise Time	t <sub>R</sub>	—	15.14	—	ns	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	—	24.29	—	ns	
Turn-Off Fall Time	t <sub>F</sub>	—	5.27	—	ns	

**Electrical Characteristics** (Q2 P-Channel) (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b> (Note 11)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-40	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	—	—	-1.0	μA	V <sub>DS</sub> = -40V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±100	nA	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS</b> (Note 11)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	-0.8	-1.3	-1.8	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	—	28	45	mΩ	V <sub>GS</sub> = -10V, I <sub>D</sub> = -3A
			30	60		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -3A
Forward Transfer Admittance	Y <sub>FS</sub>	—	16.6	—	S	V <sub>DS</sub> = -5V, I <sub>D</sub> = -3A
Diode Forward Voltage (Note 11)	V <sub>SD</sub>	—	-0.7	-1.0	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -1A
<b>DYNAMIC CHARACTERISTICS</b> (Note 12)						
Input Capacitance	C <sub>ISS</sub>	—	1,643.17	—	pF	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>OSS</sub>	—	179.13	—	pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>	—	127.82	—	pF	
Gate Resistance	R <sub>G</sub>	—	6.43	—	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge	Q <sub>G</sub>	—	33.66	—	nC	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -20V, I <sub>D</sub> = -3A
Gate-Source Charge	Q <sub>GS</sub>	—	5.54	—	nC	
Gate-Drain Charge	Q <sub>GD</sub>	—	7.30	—	nC	
Turn-On Delay Time	t <sub>D(ON)</sub>	—	6.85	—	ns	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -20V, I <sub>D</sub> = -3A
Turn-On Rise Time	t <sub>R</sub>	—	14.72	—	ns	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	—	53.65	—	ns	
Turn-Off Fall Time	t <sub>F</sub>	—	30.86	—	ns	

Notes: 11. Short duration pulse test used to minimize self-heating effect.  
12. Guaranteed by design. Not subject to production testing.

**Typical Characteristics (Q1 N-Channel)**

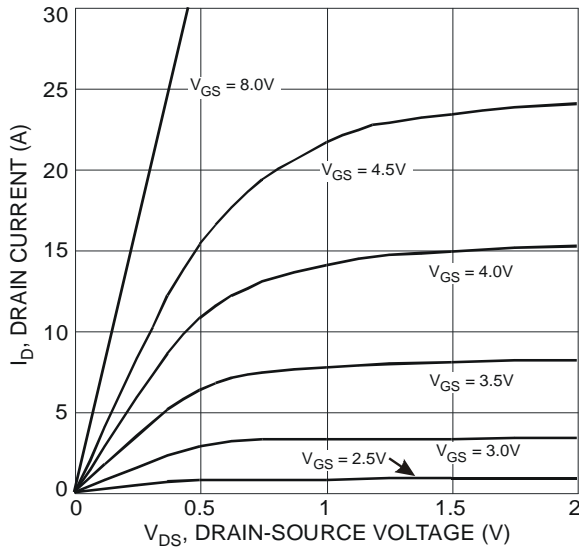


Fig. 1 Typical Output Characteristic

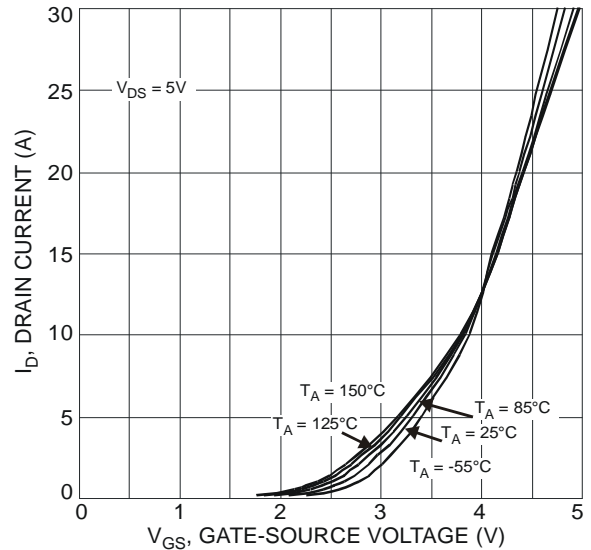


Fig. 2 Typical Transfer Characteristic

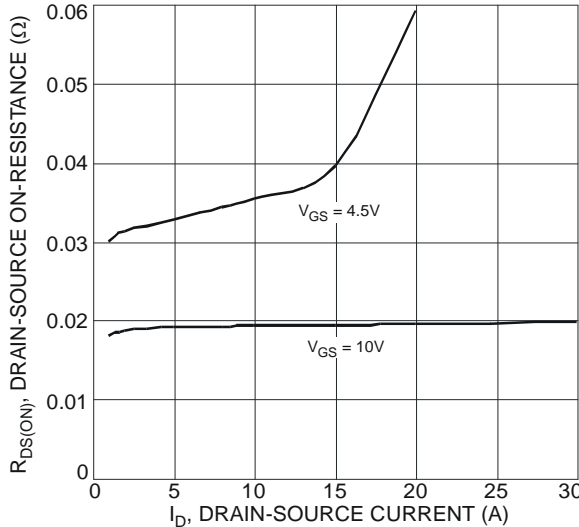


Fig. 3 Typical On-Resistance vs. Drain Current and Gate Voltage

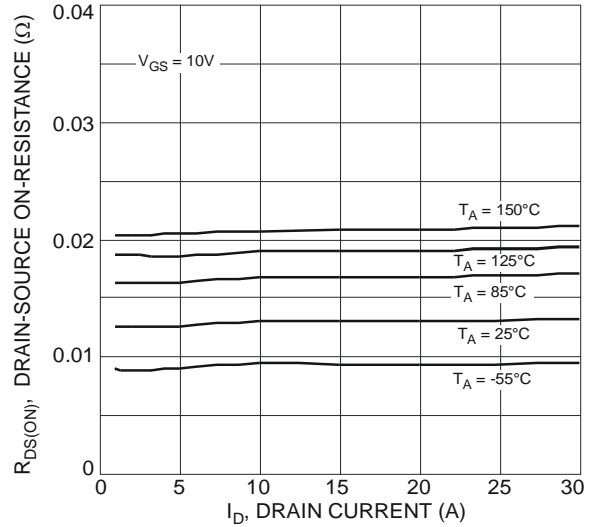


Fig. 4 Typical On-Resistance vs. Drain Current and Temperature

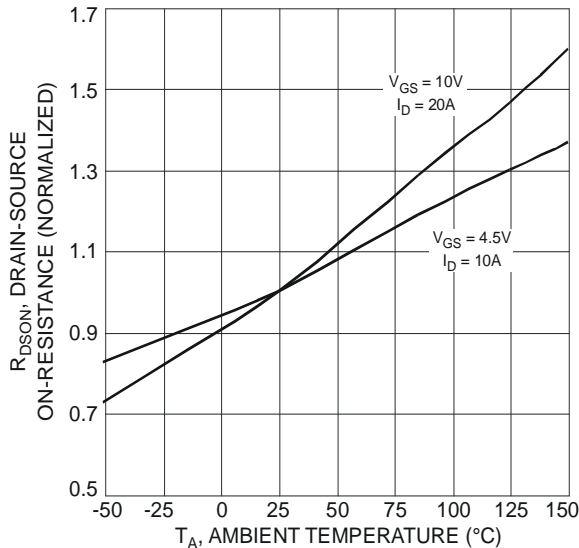


Fig. 5 On-Resistance Variation with Temperature

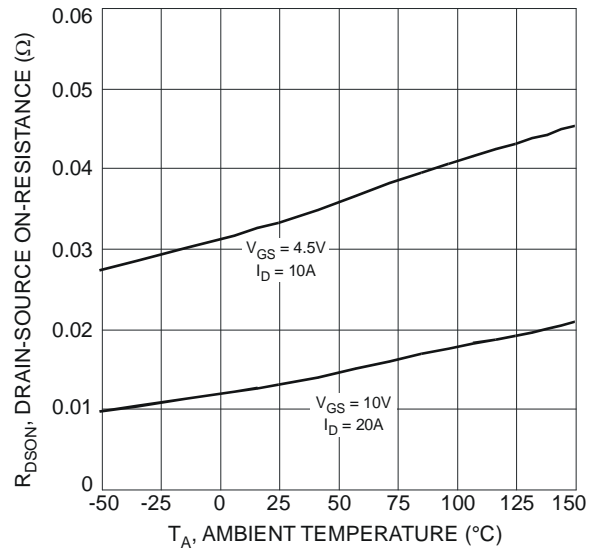


Fig. 6 On-Resistance Variation with Temperature

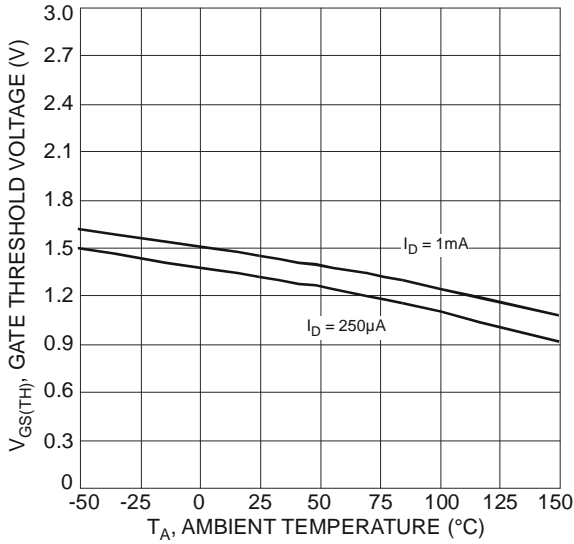


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

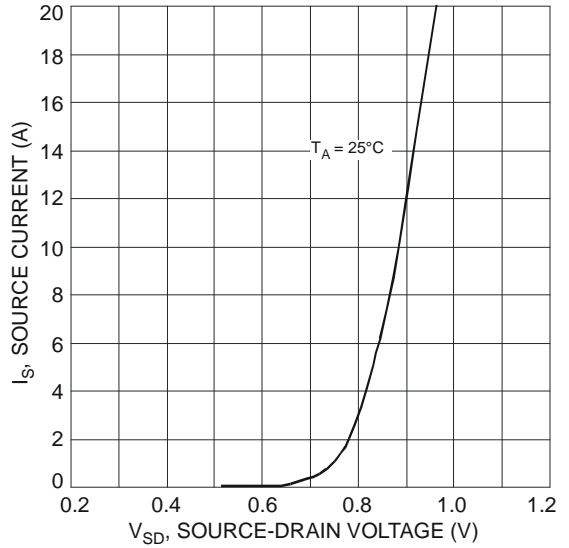


Fig. 8 Diode Forward Voltage vs. Current

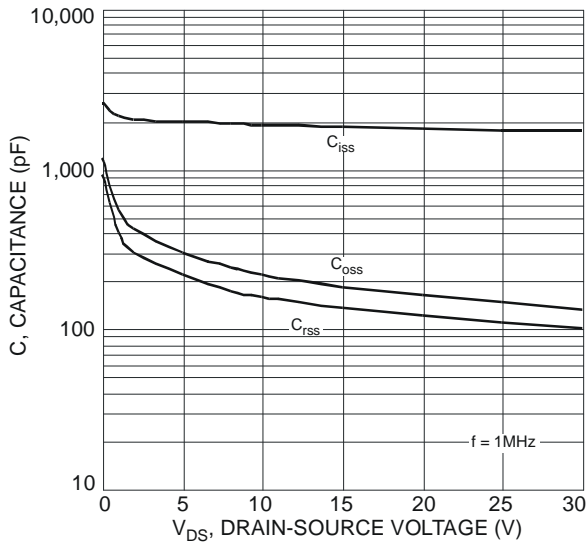


Fig. 9 Typical Total Capacitance

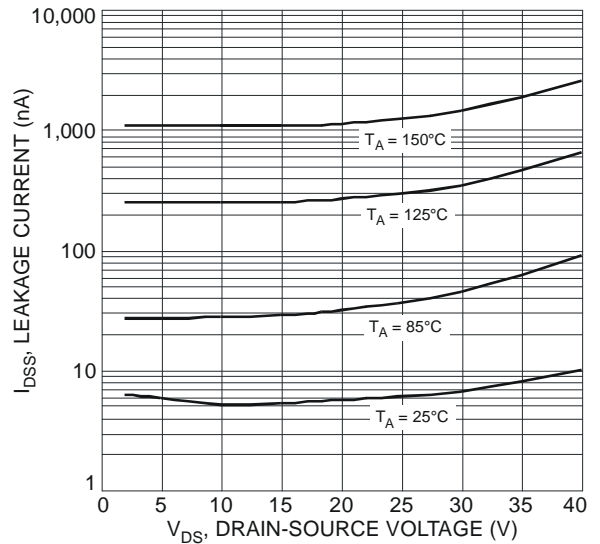


Fig. 10 Typical Leakage Current vs. Drain-Source Voltage

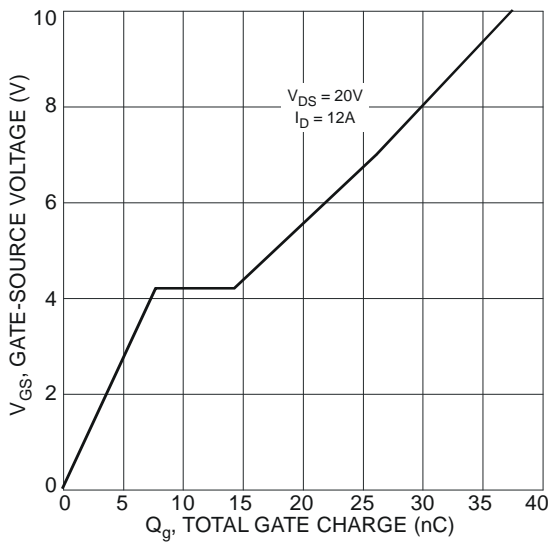


Fig. 11 Gate-Charge Characteristics

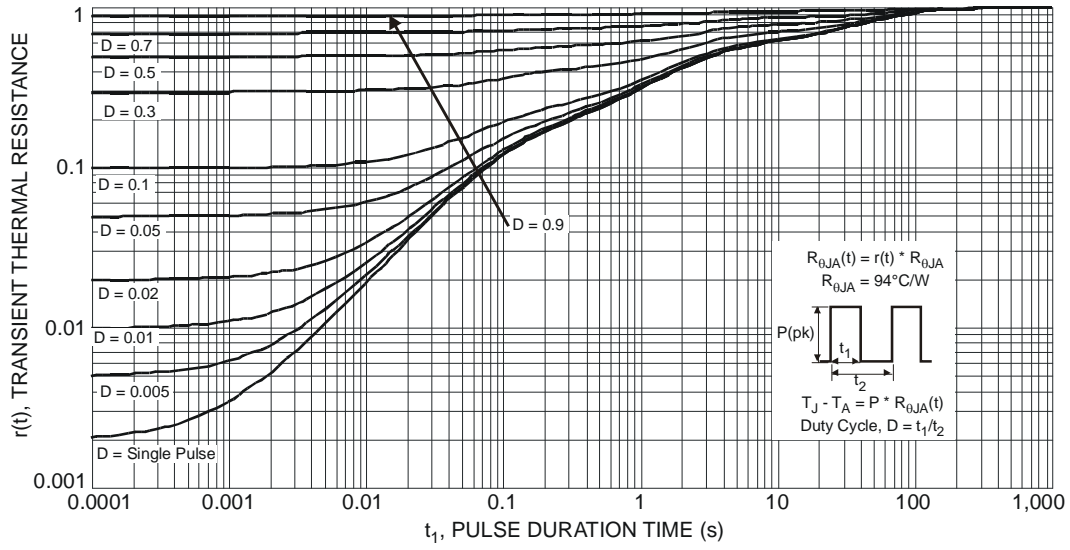


Fig. 12 Transient Thermal Response

**Typical Characteristics (Q2 P-Channel)**

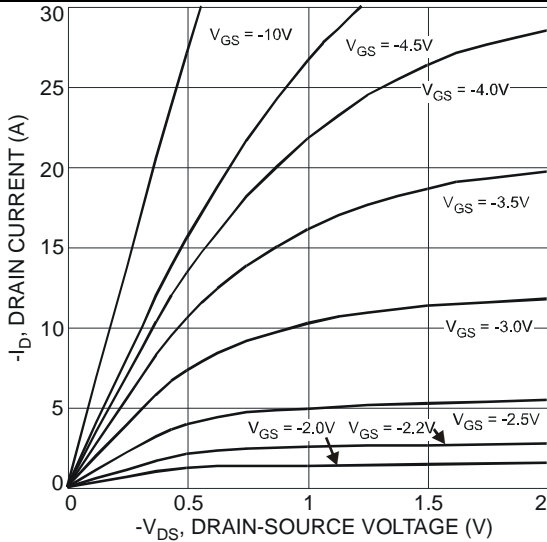


Fig. 13 Typical Output Characteristic

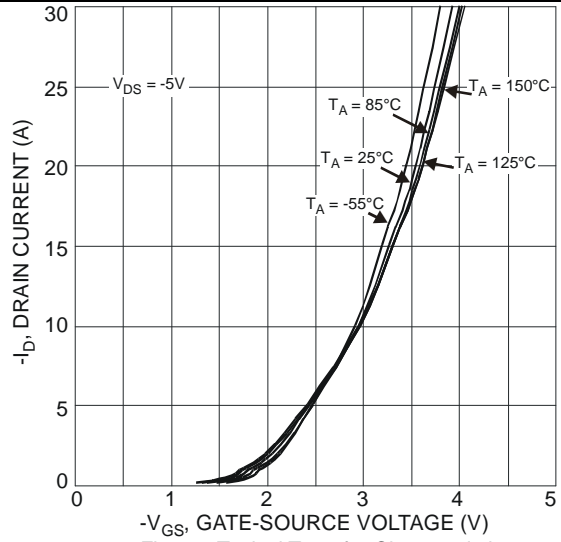


Fig. 14 Typical Transfer Characteristic

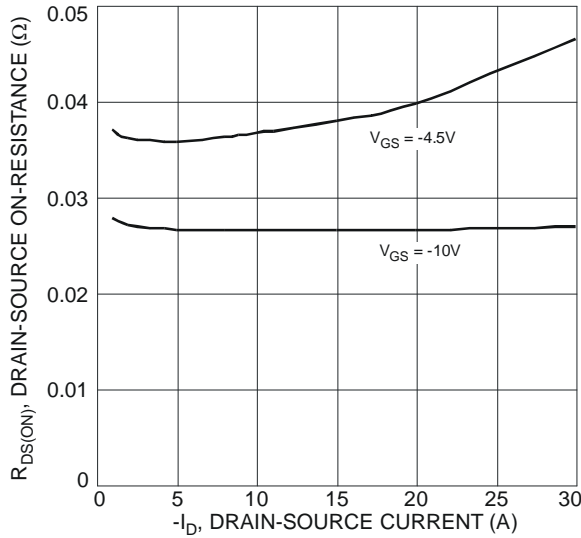


Fig. 15 Typical On-Resistance vs. Drain Current and Gate Voltage

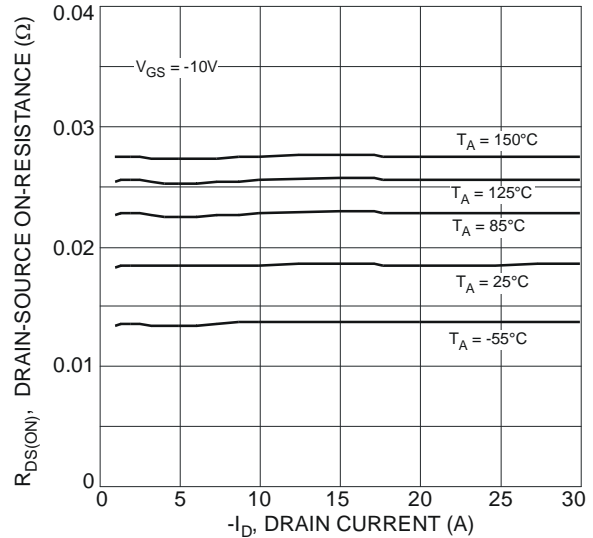


Fig. 16 Typical On-Resistance vs. Drain Current and Temperature

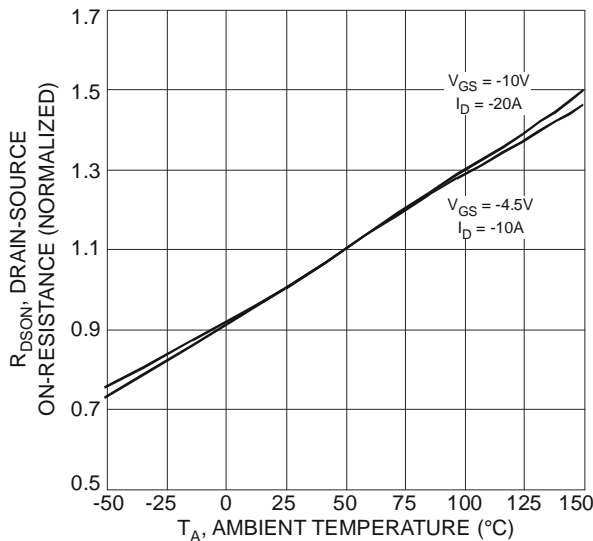


Fig. 17 On-Resistance Variation with Temperature

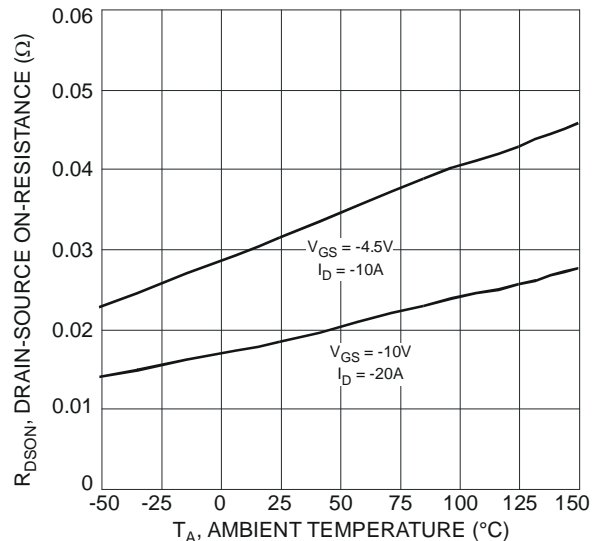


Fig. 18 On-Resistance Variation with Temperature

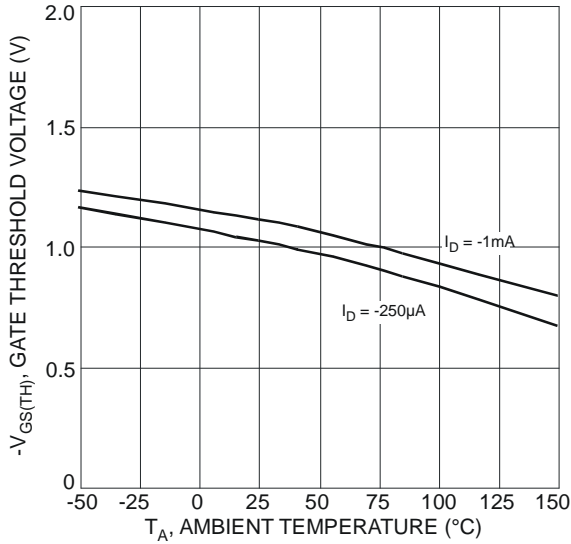


Fig. 19 Gate Threshold Variation vs. Ambient Temperature

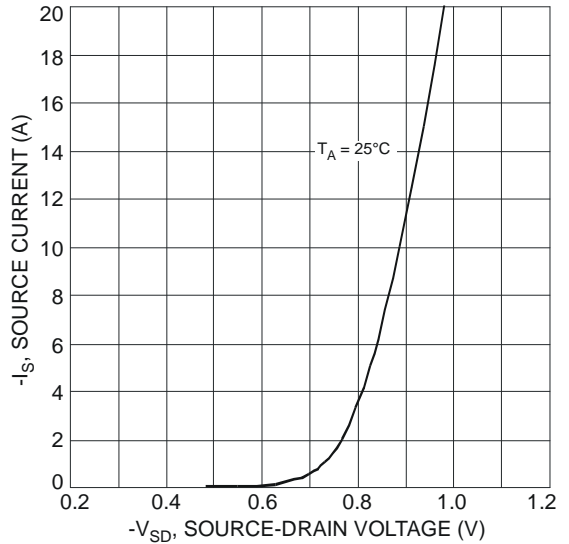


Fig. 20 Diode Forward Voltage vs. Current

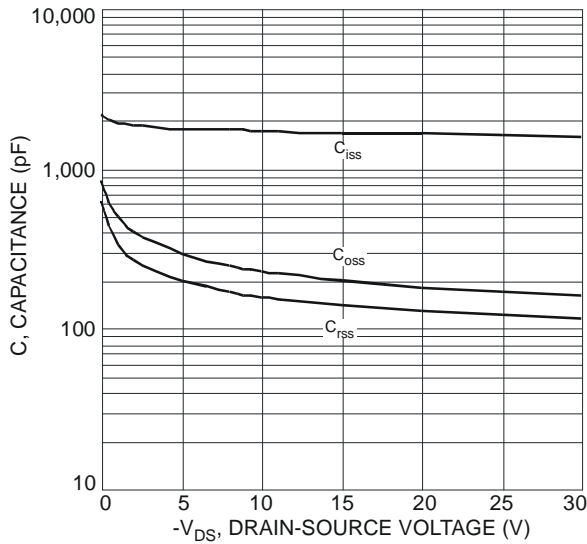


Fig. 21 Typical Total Capacitance

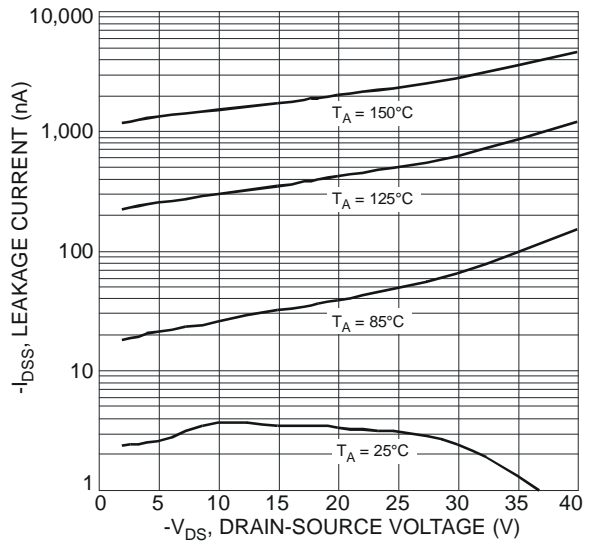


Fig. 22 Typical Leakage Current vs. Drain-Source Voltage

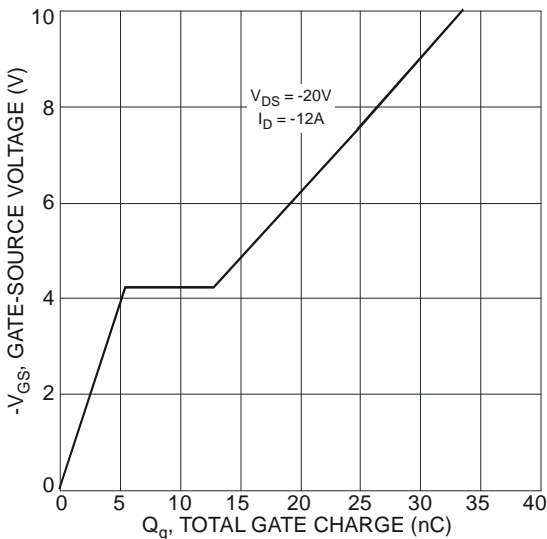


Fig. 23 Gate-Charge Characteristics



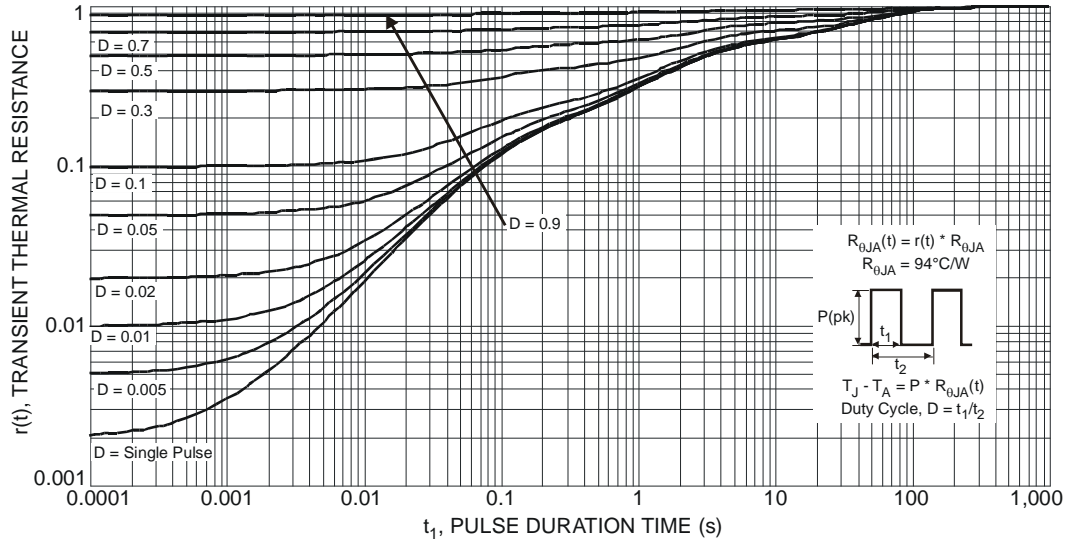
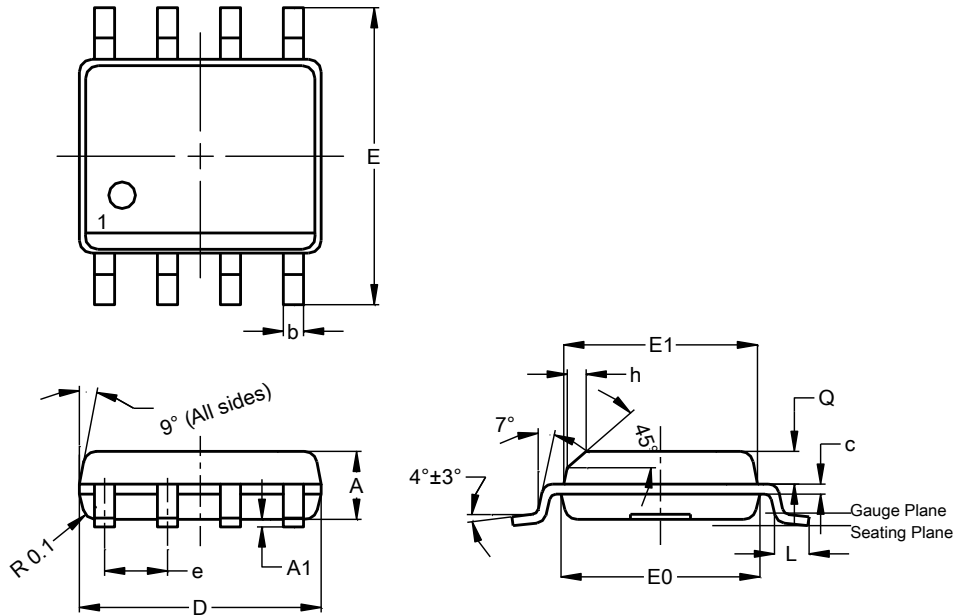


Fig. 24 Transient Thermal Response

**Package Outline Dimensions**

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

**SO-8**



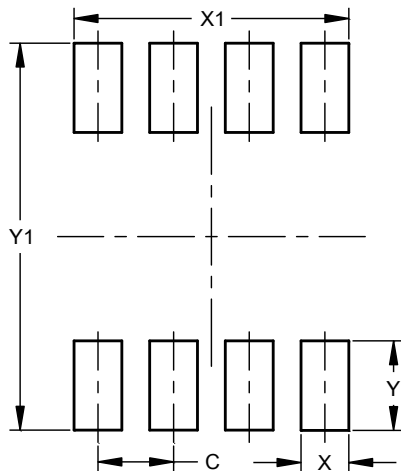
SO-8			
Dim	Min	Max	Typ
A	1.40	1.50	1.45
A1	0.10	0.20	0.15
b	0.30	0.50	0.40
c	0.15	0.25	0.20
D	4.85	4.95	4.90
E	5.90	6.10	6.00
E1	3.80	3.90	3.85
E0	3.85	3.95	3.90
e	--	--	1.27
h	-	--	0.35
L	0.62	0.82	0.72
Q	0.60	0.70	0.65

**All Dimensions in mm**

**Suggested Pad Layout**

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

**SO-8**



Dimensions	Value (in mm)
C	1.27
X	0.802
X1	4.612
Y	1.505
Y1	6.50

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